

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BAHNEN, RUDOLF	
		Examiner	Art Unit	Page 1 of 1
Francisco M. Ley		3709		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2,937,807 A	05-1960	ALBERT LORENZ	417/247
*	B	US-3,234,445 A	02-1966	CALVERT JOHN F	318/703
*	C	US-3,584,276 A	06-1971	Ringland et al.	318/721
*	D	US-3,956,650 A	05-1976	Field, II, John H.	310/156.65
*	E	US-4,312,628 A	01-1982	Yamamura, Akira	417/423.4
*	F	US-4,818,890 A	04-1989	Mose et al.	290/52
*	G	US-5,378,128 A	01-1995	Yanagisawa, Kiyoshi	418/9
*	H	US-5,793,178 A	08-1998	Biais, Fran.cedilla.ois	318/700
*	I	US-5,816,782 A	10-1998	Nagayama et al.	417/410.4
*	J	US-6,577,035 B2	06-2003	Coyac et al.	310/90
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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